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Report Template Version: V05 Report Template Revision Date: 2021-11-03

RF Exposure Evaluation Report

Report No.: Applicant: Address of Applicant:	CQASZ20220601108E-03 Shenzhen Times Innovation Technology Co., Ltd. 5th Floor, Building B, Baseus Intelligence Park, No.2008,Xuegang Rd, Gang Community, Bantian Street, Longgang District, Shenzhen.			
Equipment Under Test (EU	IT):			
EUT Name:	Baseus Encok True Wireless Earphones			
Model No.:	Baseus Encok W04			
Test Model No.:	Baseus Encok W04			
Brand Name:	Baseus			
FCC ID: Standards:	2AY37-W4 47 CFR Part 1.1307 47 CFR Part 2.1093 KDB447498 D04 Interim General RF Exposure Guidance v01			
Date of Receipt:	2022-06-30			
Date of Test:	2022-06-30 to 2022-07-07			
Date of Issue:	2022-07-11			
Test Result:	PASS*			

*In the configuration tested, the EUT complied with the standards specified above.

Tested By:	lewis zhou	TETING
	(Lewis Zhou)	ANTIDATING (COMP)
Reviewed By:	K. Liao	
·	(K Liao)	
	1.	APPROVED
Approved By:	Juns	-
	(Jack Ai)	

The test report is effective only with both signature and specialized stamp, The result(s) shown in this report refer only to the sample(s) tested. Without written approval of CQA, this report can't be reproduced except in full.



1 Version

Revision History Of Report

Report No.	Version	Description	Issue Date
CQASZ20220601108E-03	Rev.01	Initial report	2022-07-11



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3 General Information

3.1 Client Information

Applicant:	Shenzhen Times Innovation Technology Co., Ltd.
Address of Applicant:	5th Floor, Building B, Baseus Intelligence Park, No.2008,Xuegang Rd, Gangtou Community, Bantian Street, Longgang District, Shenzhen.
Manufacturer:	Shenzhen Times Innovation Technology Co., Ltd.
Address of Manufacturer:	5th Floor, Building B, Baseus Intelligence Park, No.2008,Xuegang Rd, Gangtou Community, Bantian Street, Longgang District, Shenzhen.
Factory:	Dongguan Ceesing Intelligent Device Manufacturing CoLtd
Address of Factory:	Room 301, Building 5, No. 15, Yinhu Road, Jiaoyitang, Tangxia Town, Dongguan City, Guangdong Province

3.2 General Description of EUT

Product Name:	Baseus Encok True Wireless Earphones
Model No.:	Baseus Encok W04
Test Model No.:	Baseus Encok W04
Trade Mark:	Baseus
Software Version:	V2.04
Hardware Version:	V5.0
Power Supply:	Charging Box: Li-ion battery: DC 3.7V 400mAh, Charge by DC 5V for adapter
	Earphone: Li-ion battery: DC 3.7V 35mAh, Charge by DC 3.7V for Charging box

3.3 General Description of BLE

Operation Frequency:	2402MHz~2480MHz
Modulation Type:	GFSK
Transfer Rate:	1Mbps/2Mbps
Number of Channel:	40
Product Type:	□ Mobile
Antenna Type:	Chip antenna
Antenna Gain:	5.54dBi

3.4 General Description of BT

Operation Frequency:	2402MHz~2480MHz				
Modulation Type:	GFSK, π/4DQPSK, 8DPSK				
Transfer Rate:	1Mbps/2Mbps/3Mbps				
Number of Channel:	79				
Product Type:	□ Mobile				
Antenna Type:	Chip antenna				
Antenna Gain:	5.54dBi				



4 MPE Evaluation

4.1 RF Exposure Compliance Requirement

4.1.1 Standard Requirement

447498 D04 Interim General RF Exposure Guidance v01

3.2. SAR Test Reduction Guidance

SAR test reduction procedures [Glossary] allow using a particular set of test data as representative of other, similar, test conditions. This may be applied for data within different test positions (e.g. body, head, extremity), wireless modes (e.g. Wi-Fi, cellular), and frequency bands. This test reduction process provides for the use of test data for one specific channel, while referencing to those data for demonstrating compliance in other required channels for each test position of an exposure condition, within the operating mode of a frequency band. This is limited specifically to when the reported 1-g or 10-g SAR for the mid-band or highest output power channel meets any of the following conditions.

4.1.2 Limits

SAR-based thresholds are derived based on frequency, power, and separation distance of the RF source. The formula defines the thresholds in general for either available maximum timeaveraged power or maximum time-averaged ERP, whichever is greater.

If the ERP of a device is not easily determined, such as for a portable device with a small form factor, the applicant may use the available maximum time-averaged power exclusively if the device antenna or radiating structure does not exceed an electrical length of λ /4.

As for devices with antennas of length greater than $\lambda/4$ where the gain is not well defined, but always less than that of a half-wave dipole (length $\lambda/2$), the available maximum time-averaged power generated by the device may be used in place of the maximum time-averaged ERP, where that value is not known.

The separation distance is the smallest distance from any part of the antenna or radiating structure for all persons, during operation at the applicable ERP. In the case of mobile or portable devices, the separation distance is from the outer housing of the device where it is closest to the antenna.

The SAR-based exemption formula of § 1.1307(b)(3)(i)(B), repeated here as Formula (B.2), applies for single fixed, mobile, and portable RF sources with available maximum time-averaged power or effective radiated power (ERP), whichever is greater, of less than or equal to the threshold Pth (mW).

This method shall only be used at separation distances from 0.5 cm to 40 cm and at frequencies from 0.3 GHz to 6 GHz (inclusive). Pth is given by Formula (B.2).



$$P_{\rm th} \,({\rm mW}) = \begin{cases} ERP_{20\,\rm cm} (d/20\,\rm cm)^x & d \le 20\,\rm cm \\ \\ ERP_{20\,\rm cm} & 20\,\rm cm < d \le 40\,\rm cm \end{cases}$$
(B.2)

where

$$x = -\log_{10}\left(\frac{60}{ERP_{20} \operatorname{cm}\sqrt{f}}\right)$$

and f is in GHz, d is the separation distance (cm), and ERP_{20cm} is per Formula (B.1). The example values shown in Table B.2 are for illustration only.

	Та	able B.	2—Ex	ample	Power	Thresh	holds (n	nW)	
				Di	stance	(mm)			
1	5	10	15	20	25	20	25	40	1

					Di	stance	(mm)				
		5	10	15	20	25	30	35	40	45	50
(Z	300	39	65	88	110	129	148	166	184	201	217
(MHz)	450	22	44	67	89	112	135	158	180	203	226
	835	9	25	44	66	90	116	145	175	207	240
Frequency	1900	3	12	26	44	66	92	122	157	195	236
nba	2450	3	10	22	38	59	83	111	143	179	219
Fr	3600	2	8	18	32	49	71	96	125	158	195
	5800	1	6	14	25	40	58	80	106	136	169



4.1.3 EUT RF Exposure

1) For BLE

Measurement Data

Channel	el Radiated Power (dBm) (mW)		Exclusion threshold (mW)
Lowest (2402MHz)	2.03	1.596	
Middle (2440MHz)	3.45	2.213	3.0
Highest (2480MHz)	2.24	1.675	

Remark: The Max Conducted Peak Output Power data refer to report Report No.: CQASZ20220601108E-02 BT can not simultaneous transmitting at same time.



2) For BT

Measurement Data

Channel	Radiated Power (dBm)	Maximum tune-up Power (mW)	Exclusion threshold (mW)
Lowest (2402MHz)	1.63	1.455	
Middle (2441MHz)	1.15	1.303	3.0
Highest (2480MHz)	1.25	1.334	

Remark: The Max Conducted Peak Output Power data refer to report Report No.: CQASZ20220601108E-01 BLE can not simultaneous transmitting at same time.

*** END OF REPORT ***